SLLS101B - JULY 1985 - REVISED JUNE 1999

- Bidirectional Transceivers
- Meet or Exceed the Requirements of ANSI Standards TIA/EIA-422-B and TIA/EIA-485-A and ITU Recommendations V.11 and X.27
- Designed for Multipoint Transmission on Long Bus Lines in Noisy Environments
- 3-State Driver and Receiver Outputs
- Individual Driver and Receiver Enables
- Wide Positive and Negative Input/Output Bus Voltage Ranges
- Driver Output Capability . . . ±60 mA Max
- Thermal Shutdown Protection
- Driver Positive and Negative Current Limiting
- Receiver Input Impedance . . . 12 kΩ Min
- Receiver Input Sensitivity . . . ±200 mV
- Receiver Input Hysteresis . . . 50 mV Typ
- Operate From Single 5-V Supply

description

The SN65176B and SN75176B differential bus transceivers are monolithic integrated circuits designed for bidirectional data communication on multipoint bus transmission lines. They are designed for balanced transmission lines and meet ANSI Standards TIA/EIA-422-B and TIA/EIA-485-A and ITU Recommendations V.11 and X.27.

The SN65176B and SN75176B combine a 3-state differential line driver and a differential input line receiver, both of which operate from a single 5-V power supply. The driver and receiver have active-high and active-low enables, respectively, that can be connected together externally to function as a direction control. The driver differential outputs and the receiver differential inputs are connected internally to form differential input/output (I/O) bus ports that are designed to offer minimum loading to the bus when the driver is disabled or $V_{CC} = 0$. These ports feature wide positive and negative common-mode voltage ranges, making the device suitable for party-line applications.

The driver is designed for up to 60 mA of sink or source current. The driver features positive and negative current limiting and thermal shutdown for protection from line-fault conditions. Thermal shutdown is designed to occur at a junction temperature of approximately 150°C. The receiver features a minimum input impedance of 12 k Ω , an input sensitivity of ±200 mV, and a typical input hysteresis of 50 mV.

The SN65176B and SN75176B can be used in transmission-line applications employing the SN75172 and SN75174 quadruple differential line drivers and SN75173 and SN75175 quadruple differential line receivers.

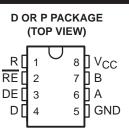
The SN65176B is characterized for operation from -40° C to 105° C and the SN75176B is characterized for operation from 0° C to 70° C.



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SLLS101B - JULY 1985 - REVISED JUNE 1999

Function Tables

DD	IVE	D
		n

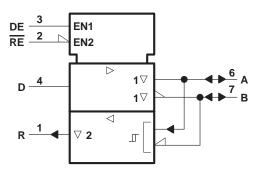
INPUT	ENABLE	OUTI	PUTS
D	DE	A B	
Н	Н	Н	L
L	Н	L	Н
Х	L	Z	Z



DIFFERENTIAL INPUTS A–B	ENABLE RE	OUTPUT R					
$V_{ID} \ge 0.2 V$	L	Н					
$-0.2 \text{ V} < \text{V}_{\text{ID}} < 0.2 \text{ V}$	L	?					
$V_{ID} \le -0.2 V$	L	L					
Х	н	Z					
Open	L	?					

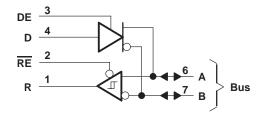
H = high level, L = low level, ? = indeterminate, X = irrelevant, Z = high impedance (off)

logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

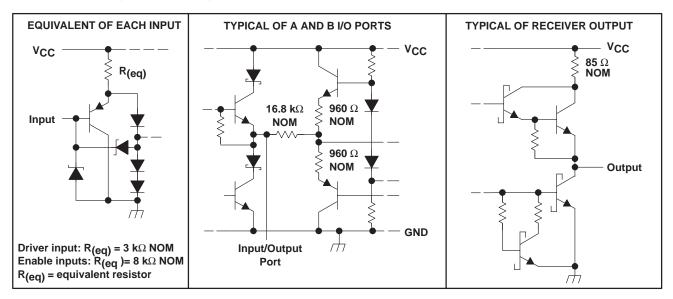
logic diagram (positive logic)





SLLS101B - JULY 1985 - REVISED JUNE 1999

schematics of inputs and outputs



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage, V _{CC} (see Note 1)	
Voltage range at any bus terminal	\ldots –10 V to 15 V
Enable input voltage, V _I	5.5 V
Package thermal impedance, θ_{JA} (see Note 2): D package	197°C/W
P package	104°C/W
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C
Storage temperature range, T _{stg}	. −65°C to 150°C

⁺ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. All voltage values, except differential input/output bus voltage, are with respect to network ground terminal.

2. The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.

MIN TYP MAX UNIT Supply voltage, V_{CC} 4.75 5.25 5 V 12 Voltage at any bus terminal (separately or common mode), VI or VIC V -7 D, DE, and RE V High-level input voltage, VIH 2 D, DE, and RE V Low-level input voltage, VIL 0.8 V Differential input voltage, VID (see Note 3) ±12 Driver -60 mΑ High-level output current, IOH Receiver -400 μΑ Driver 60 Low-level output current, IOL mΑ 8 Receiver SN65176B -40 105 Operating free-air temperature, TA °C SN75176B 70 0

recommended operating conditions

NOTE 3: Differential-input/output bus voltage is measured at the noninverting terminal A with respect to the inverting terminal B.



SLLS101B – JULY 1985 – REVISED JUNE 1999

DRIVER SECTION

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

	PARAMETER	TEST CON	DITIONS [†]	MIN	TYP‡	MAX	UNIT
VIK	Input clamp voltage	lı = – 18 mA				-1.5	V
VO	Output voltage	IO = 0		0		6	V
VOD1	Differential output voltage	IO = 0		1.5	3.6	6	V
	Differential output voltage	R _L = 100 Ω,	See Figure 1	1/2 V _{OD1} or 2¶			V
		R _L = 54 Ω,	See Figure 1	1.5	2.5	5	V
V _{OD3}	Differential output voltage	See Note 4		1.5		5	V
∆ V _{OD}	Change in magnitude of differential output voltage§					±0.2	V
Voc	Common-mode output voltage	R_L = 54 Ω or 100 Ω,	See Figure 1			+3 -1	V
∆ Voc	Change in magnitude of common-mode output voltage§					±0.2	V
10	Output ourrest	Output disabled,	V _O = 12 V			1	mA
10	Output current	See Note 5	$V_{O} = -7 V$			-0.8	mA
IIН	High-level input current	VI = 2.4 V				20	μA
۱ _{IL}	Low-level input current	VI = 0.4 V				-400	μA
		$V_{O} = -7 V$				-250	
	Short-circuit output current	$V_{O} = 0$	V _O = 0			150	mA
los	Short-circuit output current	$A^{O} = A^{O}$				250	IIIA
		V _O = 12 V				250	
	Supply current (total package)	No load	Outputs enabled		42	70	mA
ICC	Supply current (total package)	ino luau	Outputs disabled		26	35	IIIA

[†] The power-off measurement in ANSI Standard TIA/EIA-422-B applies to disabled outputs only and is not applied to combined inputs and outputs. [‡] All typical values are at $V_{CC} = 5 V$ and $T_A = 25^{\circ}$ C.

§ Δ|V_{OD}| and Δ|V_{OC}| are the changes in magnitude of V_{OD} and V_{OC}, respectively, that occur when the input is changed from a high level to a low level.

 \P The minimum V_{OD2} with a 100- Ω load is either 1/2 V_{OD1} or 2 V, whichever is greater.

NOTES: 4. See ANSI Standard TIA/EIA-485-A, Figure 3.5, Test Termination Measurement 2.

5. This applies for both power on and off; refer to ANSI Standard TIA/EIA-485-A for exact conditions. The TIA/EIA-422-B limit does not apply for a combined driver and receiver terminal.

switching characteristics, V_{CC} = 5 V, R_L = 110 k Ω , T_A = 25°C (unless otherwise noted)

						-	
	PARAMETER	TEST CONDITIONS		MIN	TYP	MAX	UNIT
td(OD)	Differential-output delay time	$R_L = 54 \Omega$, See Figure 3			15	22	ns
^t t(OD)	Differential-output transition time			20	30	ns	
^t PZH	Output enable time to high level	See Figure 4			85	120	ns
t _{PZL}	Output enable time to low level	See Figure 5			40	60	ns
^t PHZ	Output disable time from high level	See Figure 4			150	250	ns
^t PLZ	Output disable time from low level	See Figure 5			20	30	ns



SLLS101B - JULY 1985 - REVISED JUNE 1999

SYMBOL EQUIVALENTS							
DATA-SHEET PARAMETER	TIA/EIA-422-B	TIA/EIA-485-A					
VO	V _{oa,} V _{ob}	V _{oa,} V _{ob}					
IVOD1	Vo	Vo					
IVOD2	V _t (R _L = 100 Ω)	$V_t (R_L = 54 \Omega)$					
Ινοd3Ι		V _t (Test Termination Measurement 2)					
	$ V_t - \overline{V}_t $	$ V_t - \overline{V}_t $					
Voc	V _{OS}	V _{os}					
	$ V_{OS} - \overline{V}_{OS} $	$ V_{OS} - \overline{V}_{OS} $					
IOS	I _{sa} , I _{sb}						
lo	I _{xa} , I _{xb}	l _{ia} , l _{ib}					

RECEIVER SECTION

electrical characteristics over recommended ranges of common-mode input voltage, supply voltage, and operating free-air temperature (unless otherwise noted)

	PARAMETER	TEST CO	ONDITIONS	MIN	TYP [†]	MAX	UNIT
VIT+	Positive-going input threshold voltage	V _O = 2.7 V,	$I_{O} = -0.4 \text{ mA}$			0.2	V
VIT-	Negative-going input threshold voltage	V _O = 0.5 V,	I _O = 8 mA	-0.2‡			V
V _{hys}	Input hysteresis voltage (VIT+-VIT-)				50		mV
VIK	Enable Input clamp voltage	lı = -18 mA				-1.5	V
Vон	High-level output voltage	V _{ID} = 200 mV, See Figure 2	I _{OH} = -400 μA,	2.7			V
VOL	Low-level output voltage	$V_{ID} = -200 \text{ mV},$ See Figure 2	I _{OL} = 8 mA,			0.45	V
loz	High-impedance-state output current	$V_{O} = 0.4 \text{ V to } 2.4 \text{ V}$				±20	μA
		Other input = 0 V,	VI = 12 V			1	mA
1	Line input current	See Note 6	$V_{I} = -7 V$			-0.8	ША
ЧΗ	High-level enable input current	VIH = 2.7 V				20	μA
ΙL	Low-level enable input current	V _{IL} = 0.4 V				-100	μA
rı	Input resistance	V _I = 12 V		12			kΩ
los	Short-circuit output current			-15		-85	mA
	Supply surrent (total paskage)	No load	Outputs enabled		42	55	m۸
ICC	Supply current (total package)	INU IUAU	Outputs disabled		26	35	mA

[†] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

[‡] The algebraic convention, in which the less positive (more negative) limit is designated minimum, is used in this data sheet for common-mode input voltage and threshold voltage levels only.

NOTE 6: This applies for both power on and power off. Refer to EIA Standard TIA/EIA-485-A for exact conditions.



SLLS101B – JULY 1985 – REVISED JUNE 1999

switching characteristics, V_{CC} = 5 V, C_L = 15 pF, T_A = 25°C

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
^t PLH	Propagation delay time, low- to high-level output			21	35	ns
^t PHL	Propagation delay time, high- to low-level output	$V_{ID} = 0$ to 3 V, See Figure 6		23	35	ns
^t PZH	Output enable time to high level	Soo Eiguro 7		10	20	ns
t _{PZL}	Output enable time to low level	See Figure 7		12	20	ns
^t PHZ	Output disable time from high level	See Figure 7		20	35	ns
^t PLZ	Output disable time from low level	See Figure 7		17	25	ns

PARAMETER MEASUREMENT INFORMATION

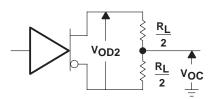


Figure 1. Driver V_{OD} and V_{OC}

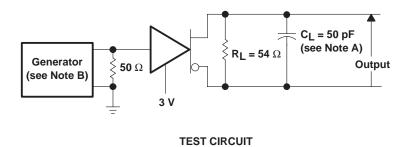
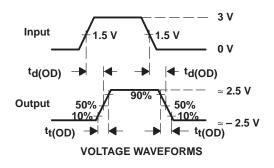


Figure 2. Receiver VOH and VOL



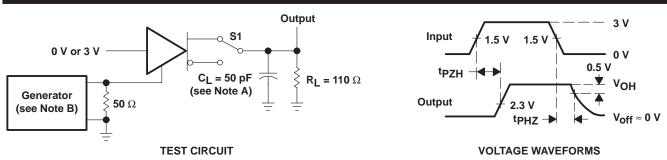
NOTES: A. $C_{\mbox{L}}$ includes probe and jig capacitance.

B. The input pulse is supplied by a generator having the following characteristics: PRR \leq 1 MHz, 50% duty cycle, t_f \leq 6 ns, t_f \leq 6 ns, Z_O = 50 Ω .

Figure 3. Driver Test Circuit and Voltage Waveforms

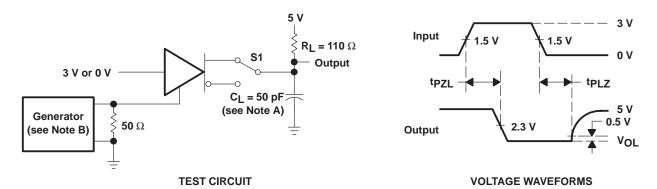


SLLS101B - JULY 1985 - REVISED JUNE 1999



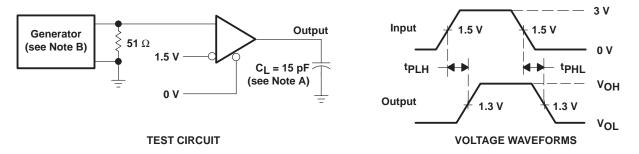
- NOTES: A. CL includes probe and jig capacitance.
 - B. The input pulse is supplied by a generator having the following characteristics: PRR \leq 1 MHz, 50% duty cycle, t_f \leq 6 ns, t_f \leq 6 ns, Z_Q = 50 Ω .

Figure 4. Driver Test Circuit and Voltage Waveforms



- NOTES: A. C₁ includes probe and jig capacitance.
 - B. The input pulse is supplied by a generator having the following characteristics: PRR \leq 1 MHz, 50% duty cycle, t_f \leq 6 ns, t_f \leq 6 ns, Z_O = 50 Ω .

Figure 5. Driver Test Circuit and Voltage Waveforms

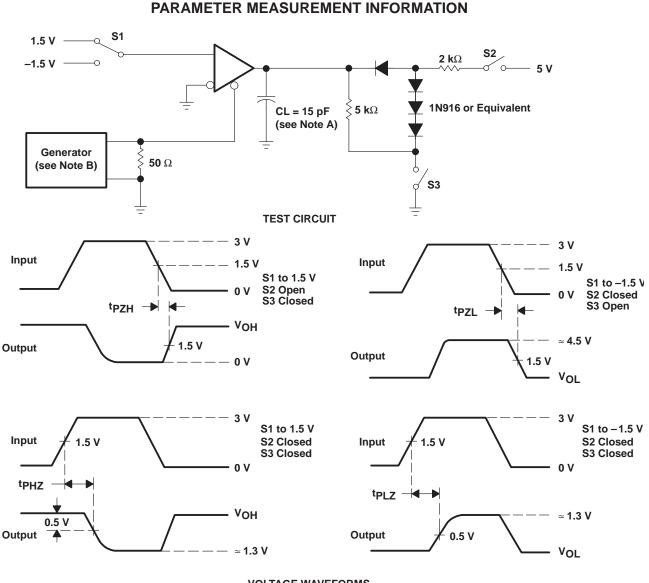


- NOTES: A. CL includes probe and jig capacitance.
 - B. The input pulse is supplied by a generator having the following characteristics: PRR \leq 1 MHz, 50% duty cycle, t_f \leq 6 ns, t_f \leq 8 ns, t_f \leq 8

Figure 6. Receiver Test Circuit and Voltage Waveforms



SLLS101B – JULY 1985 – REVISED JUNE 1999



VOLTAGE WAVEFORMS

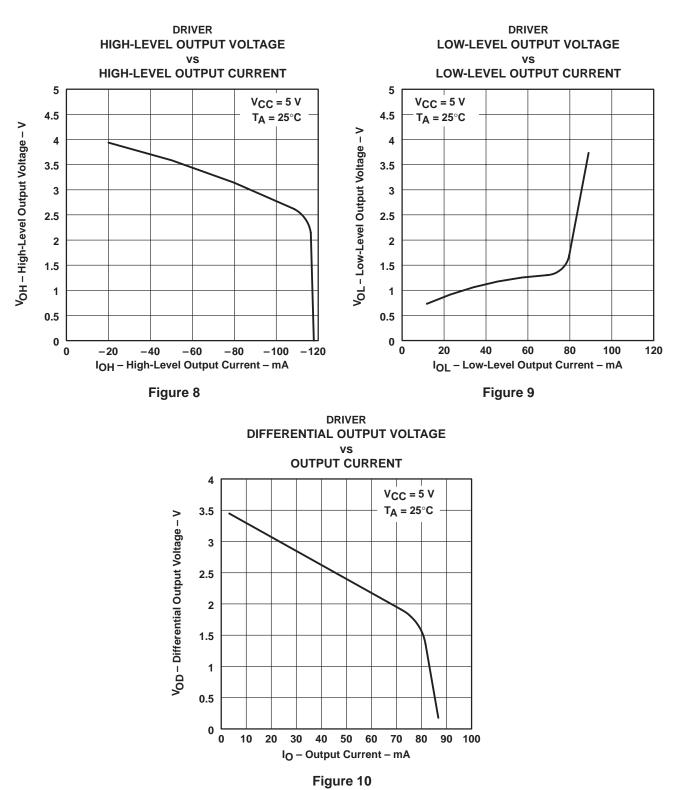
NOTES: A. CL includes probe and jig capacitance.

B. The input pulse is supplied by a generator having the following characteristics: PRR \leq 1 MHz, 50% duty cycle, t_r \leq 6 ns, t_f \leq 8 ns, t_f \leq 8

Figure 7. Receiver Test Circuit and Voltage Waveforms



SLLS101B - JULY 1985 - REVISED JUNE 1999

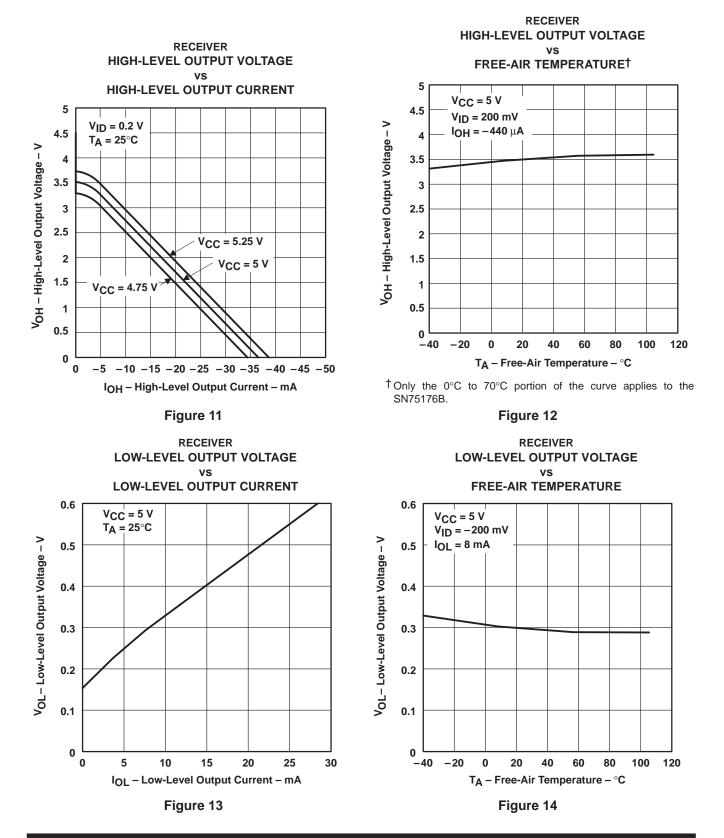


TYPICAL CHARACTERISTICS



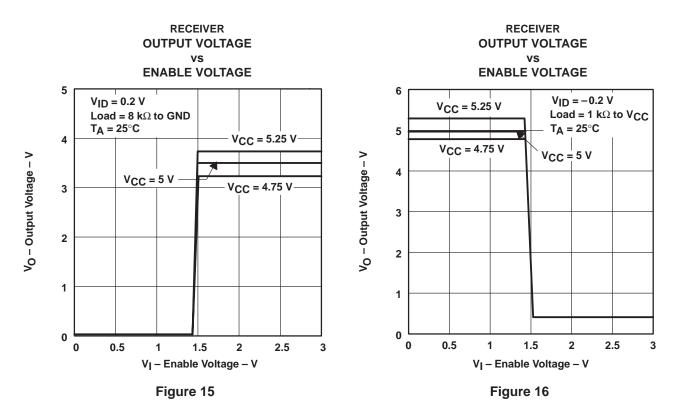
SLLS101B – JULY 1985 – REVISED JUNE 1999

TYPICAL CHARACTERISTICS



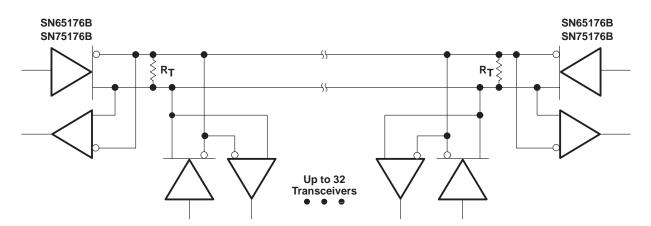


SLLS101B - JULY 1985 - REVISED JUNE 1999



TYPICAL CHARACTERISTICS

APPLICATION INFORMATION



NOTE A: The line should be terminated at both ends in its characteristic impedance (R_T = Z_O). Stub lengths off the main line should be kept as short as possible.

Figure 17. Typical Application Circuit



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